



Review on Mineral Characterization of Precambrian Charnockites using PIXE Technique

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9 Abstract:

Particle Induced X-ray Emission (PIXE) has been applied to an analytical tool for long range 11 of major, minor, trace and REE elemental analysis in Precambrian Charnockites. PIXE is 12 sensitive and non-destructive method for some elemental analysis in a variety of metamorphic 13 Precambrian Charnockite rocks down to levels of a few parts per million and it is not valid for 14 all remaining elements in the composition. The elements in the Precambrian Charnokite rock Cl, 15 K, Ca, Ti, V, Cr, Mn, Fe, Ni, Cu, Zn, Se, Br, Rb, Sr, Y, Zr, Nb, Mo, Ru, Ag, Pb are identified 16 without exact values by PIXE but the elements minor Be and F, major elements Na, Mg, Al, 17 Si, P, Ba and traces of Sc, Ce, Co, Sn, W, Ge, Ga, Au, Th, U and REE not detected due to 18 various reasons even though there present in the Charnockites, because of PIXE which is 19 operation at 3MeV energy and characterization material of Charnockite mineral investigated. In 20 mineral characterization of Charnockite rocks, elemental errors in concentration of the 21 compositions explained by comparing with present other non nuclear technique and previous 22 nuclear technique studies.

Keywords; PIXE Technique, Metamorphic, Precambrian, Charnockites, Multi elemental
 analysis, Mineral characterization, Review.

26 1. Introduction

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28 The geological history of the earth is primarily divided into three periods. They are 1) 29 Archian period 2) Proterozoic period 3) Phanerozoic period. The phonerozoic era is further divided into 1. Paleozoic (ancient life) 2. Mesozoic (middle life) and 3. Genozoic (recent life) 30 31 periods. This classification is done on the basis of fossils found in each period. Again the first period of Paleozoic era is called Cambrian period and hence the time before the phanorozic 32 era is also called pre-cambrian period which dates back to more than 2.5 billion years. As is 33 well known the earth is conventionally divided into crust, mantle and core. The crust is 34 further divided into three major categories continental, transitional and Oceanic. Geochemical 35 and Petrologic investigations of Precambrian mafic Radha Krishna (2008) metamorphic rocks 36 37 containing iron and magnesium) igneous rocks play an important role in establishing the 38 evolution of the crust. Most Precambrian exposures Srivastava, and Ahmad (2008) (shields or 39 cratons) contain metamorphic rocks and of rock were changed. 40





The charnockite series is a group of igneous rocks French, et. al., (2008) variably 41 metamorphosed. They are widely distributed and occupy an important place in the geology of 42 India is the main sources for creation of continental crust. Calc-alkaline rocks typically are 43 44 found above subduction zones, commonly in volcanic areas, and particularly on such area on 45 continental crust. A widely accepted theory of the development of earth's crust states that the 46 early earth would have had a proto crust formed from ultra mafic and felsic layers.

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The samples analysed using PIXE in the present study are collected in a very 48 interesting context. Geologically the Visakhapatnam city is characterized by rocks termed as 49 50 Eastern Ghats. The rocks are Precambrian age and comprise mainly Khondalites, Lepitynites, 51 Poryxene Granulites and Charnockites and all of them have undergone metamorphosis. Among these, charnockites are termed as upper mantle basic igneous rocks and are emplaced 52 into proto crustal rocks during Precambrian times. In this way the charnockites sometimes 53 may contain the relict bodies of earlier crustal rocks (proto crust). The proto crust is derived 54 from primitive oceans which are also called intra-cratonic sea water bodies. 55

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57 The samples chosen for analysis are collected from the central portion of a charnockite 58 hill Rao, and Babu, (2008) near Visakhapatnam airport during a demolition operation for extension of the airport. A big lenticular mass of relict lithological body which is 59 compositionally and physically different from the host charnockite was observed in this 60 central portion of the hill. This body is believed to be the caught up body of the early crustal 61 layer (possibly proto crust).Such samples are rare. PIXE technique is chosen for the trace 62 elemental analysis Kullerud, and Steffen, (1979) of these rare samples as it is a highly 63 64 sensitive and non destructive method for the simultaneous multi elemental analysis. Elements 65 present in ppm levels can be detected efficiently with this technique.

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67 The experimental work was carried out using the 3Mev particle accelerator facility at 68 the institute of physics, Bhubaneswar. The characteristic X-rays were detected with Si (Li) detector. The data analysis was carried out and concentrations of various elements detected 69 70 were determined using GUPIX software and different elements were detected in varied 71 concentrations. On the basis of the concentrations of these different trace elements obtained using PIXE Technique, a geochemical analysis of the rock samples was performed and 72 73 interpreted for the genetic significance substantiating the information from previous 74 literature. 75

76 2. Experimental Details and Data Analysis.

77 Some of the trace elements are present in minute amounts in geological samples. Earlier 78 79 it was very difficult to measure their precise concentrations because of non availability of 80 sophisticated analytical methods. They were therefore described as occurring in traces, hence the term 'trace element'. With the invention of many modern analytical techniques Sie, et. al., 81 (1989) like Atomic Absorption Spectrometry (AAS) Instrumental Neutron Activation 82 Analysis (INAA), Rutherford Back Scattering (RBS), X-Ray Fluorescence (XRF), Energy 83 Dispersive X-Ray Fluorescence (EDXRF), Auger Electron Spectroscopy (AES), Particle 84 Induced Gamma Ray Emission (PIGE), Particle Induced X-Ray Emission (PIXE), 85 Wavelength Dispersive X-Ray Fluorescence (WDXRF) etc. It has become possible to 86 87 estimate the concentrations of trace elements in ppm and ppb levels. These analytical techniques have the capability to measure all the trace elements present even in the smallest 88 geological samples Malmqvist, (1987) with great precession and accuracy. The term trace is a 89





traditionally followed through it has become scientifically obsolete owing to the availability improved techniques. Among all the afore-mentioned techniques, PIXE Technique has its own advantages over the other techniques. From analytical point of view, techniques for the identification of trace elements and evaluation of their concentrations are categorized into destructive and non destructive techniques. Tangi, (1998) Chemical analysis and AAS are the two well known methods under the former category. Generally these methods require large amounts of sample and are tedious as they involve element-by-element analysis.

98 PIXE and XRF are the both the methods based on x-ray emission are have several 99 features in common. From sensitive point of view PIXE has certain superiority. Moreover the 100 bremsstrahlung produced in PIXE is a secondary effect and hence is also the principle 101 determinant of detection limits. The low bremsstrahlung in PIXE enables parts per million sensitivities, superior to its sister techniques. Due to high sensitivity and multi elemental 102 103 analysis capability, PIXE has found applications in trace elemental analysis Luciana (1999) of samples from almost every conceivable field of scientific or technical interest. Some of 104 these fields are Biomedicine, Environment, Archaeology, Material science, Forensic studies, 105 106 Industrial applications and Geology.

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The present study is aimed at estimating the concentrations of different trace elements 108 in geological samples of Precambrian charnockite hill near Visakhapatnam airport using 109 particle induced X-ray emission (PIXE) technique. These experiments are carried out using 110 3MV pelletron accelerator facility at the Institute of physics, Bhubaneswar, Protons with 111 3Mev energy are used to excite the samples. The samples are mounted on an Aluminium 112 target holder (a ladder arrangement). Then the target holder is inserted into the scattering 113 chamber and the irradiation is carried out in vacuum conditions. A collimated proton beam of 114 2 mm diameter is made to fall on to the sample. The beam current is kept at 20 nA. The 115 samples on the target holder which are to be exited or positioned in this scattering chamber at 116 an angle of 45° with respect to the direction of the proton beam. The position of the sample 117 relative to the beam direction is adjusted properly by viewing through a window provided in 118 the scattering chamber. A high resolution Si (Li) detector (160 eV FWHM at 5.9 KeV 119 energy) is employed in the present experiments to record the X-ray spectrum. The detector is 120 placed at an angle of 90⁰ with respect to the beam direction. The output of the Si (Li) detector 121 122 is coupled to data acquisition system, which records the X-ray spectrum. The spectrum of each sample is recorded for a sufficiently long time so as to ensure goods statistics. During 123 124 the irradiation of each sample the charge collected and the average beam current is noted.

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126 The Guelph PIXE (GUPIX) software package is used to analyse the spectra utilizing a standard Marquardt non-linear least square fitting procedure. This package is provision to 127 identify different elements present in the sample and to estimate their relative intensities. 128 129 Using this GUPIX software package the X-ray intensities of different elements are converted 130 into the respective concentrations using a standardization technique involving fundamental 131 parameters, pre determined instrument constants and input parameters such as solid angle, charge collected etc. Comparing the concentrations of Yttrium obtained in the present work 132 with the known concentration of Yttrium added to the sample, the reliability of the input 133 parameters is checked. To assure the reliability of experimental system and other parameters, 134 135 in the same experimental conditions, the PIXE spectrum is recorded with NIST certified reference material and the relative concentrations of different elements are estimated using 136 137 GUPIX software package. The relative concentrations of different elements thus obtained in 138 the present experiment for the above standard samples are compared with the certified 139 concentrations supplied by NIST. Good agreement Table-1 with in experimental uncertainties





140 is observed and this shows the reliability of the present experimental system and use of

- 141 GUPIX software package in the data analysis.
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Table-1. PIXE spectrum is recorded with NIST certified reference material-Apple Leaves-1515.

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Elements	Concentration (ppm)		
	Certified values	Measured values	
K	1.48±0.05	1.60±0.02	
Са	1.615±0.26	1.53±0.02	
Mn	48.5±2.4	54.0±3.0	
Fe	88.1±4.5	83.0±5.0	
Си	5.3±0.4	5.60±0.24	
Zn	12.9±0.7	12.5±0.03	
Se	0.06±0.01	0.05±0.009	
Rb	9.3±1.0	10.2±1.50	
Pb	0.54±0.08	0.47±0.02	

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This deals with the detailed explanation of the advantages of PIXE over other analytical
techniques, principle and technical minutiae of the PIXE technique, experimental setup,
sample preparation and data analysis.

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152 3. Results and discussions

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The PIXE spectrum fig; 1-7 of the geological samples G1 to G7 collected from the interior of the charnockite rock recorded by Si (Li) detector. The concentrations in ppm of these various elements in each sample were determined using the GUPIX software .These concentrations are presented with errors in tables 2-13.















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Figure-7; PIXE Spectrum of sample G7

The PIXE spectrum of the geological samples G1 to G7 collected from the interior of 174 the Charnockite rock recorded by Si (Li) detector. These concentrations are presented with 175 errors in Table-9. Another attempt is made to analyze the samples using an atomic absorption 176 photo spectrometer and same elements are reported using the method of AAS and the same 177 standard also employed for a method of AAS also. The data generated the AAS method has 178 been used to compare the PIXE results for its evaluation purpose. In this paragraph, each 179 element is considered in evaluating PIXE as per that element is concentrated. It is observed 180 that the results obtained by AAS are close which already published data on Charnockites in 181 182 various journals.

The possibility of increasing accuracy of PIXE in analysing samples of complex matrix like Charnockite has been discussed and suggestions are made. So, the following tables presents the elements which are close to elements having moderate errors and elements which are highly erroneous not detected. Using this data, the Charnockite hill from where the samples are collected has been attempted. to understand the chemical nature followed by genetic implications. The reasons behind the poor performance of PIXE with respect to certain elements have been tried to explain.

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202	Table-2;	G1	sample	elements	and
203	concentrat	ions			

S.NO	Element	G1
1	Cl	394.1±16.5
2	K	4080±28.2
3	Ca	2229±25.9
4	Ti	1394±11.6
5	V	17.92±4.8
6	Cr	16.63±2.3
7	Mn	18.623.9±
8	Fe	5200±20.3
9	Ni	10.96±3.7
10	Cu	BDL
11	Zn	9.147±3.3
12	Se	6.3±65±2.5
13	Br	4±2.2
14	Rb	48.87±6.0
15	Sr	38.5±5.4
16	Y	BDL
17	Zr	95.91±9.8
18	Nb	7.035±3.1
19	Мо	BDL
20	Ru	BDL
21	Ag	BDL
22	Pb	32.93±15.6

207	Table-3;	G2	sample	elements	and
208	concentra	tions			
209					

S.No	Element	<i>G2</i>
1	Cl	399.6±17.1
2	K	4187±25.1
3	Ca	2281±22.8
4	Ti	1271±9.3
5	V	23.69±4.1
6	Cr	38.53±2.1
7	Mn	34.71±3.7
8	Fe	6575±21.0
9	Ni	11.43±3.7
10	Cu	BDL
11	Zn	18.21±3.5
12	Se	BDL
13	Br	12.17±2.93
14	Rb	42.08±6.1
15	Sr	28.6±4.6
16	Y	12.64±4.5
17	Zr	20.86±6.0
18	Nb	9.812±3.9
19	Мо	24.34±6.3
20	Ru	BDL
21	Ag	12.36±9.0
22	Pb	38.35±17.3





213	Table-4;	G3	sample	elements	and
214	concentrat	ions			

S.NO	Element	<i>G3</i>
1	Cl	379±16.5
2	K	4148±26.1
3	Са	2637±25.6
4	Ti	1109±9.3
5	V	7.85±4.0
6	Cr	15.16±2.1
7	Mn	34.31±3.7
8	Fe	5649±19.8
9	Ni	10.06±3.39
10	Cu	6.1±2.7
11	Zn	14.23±3.0
12	Se	BDL
13	Br	11.82±2.85
14	Rb	62.73±6.0
15	Sr	44.61±4.9
16	Y	BDL
17	Zr	23.6±6.1
18	Nb	BDL
19	Мо	BDL
20	Ru	BDL
21	Ag	BDL
22	Pb	17.68±7.7

218 Table-5; G4 sample elements and219 concentrations220

S.NO	Element	G 4
1	Cl	403.5±19.5
2	K	4246±29.3
3	Ca	2754±28.1
4	Ti	13.67±11.3
5	V	BDL
6	Cr	16.93±2.5
7	Mn	33.68±4.1
8	Fe	5838±22.2
9	Ni	8.94±3.92
10	Cu	BDL
11	Zn	14.41±3.5
12	Se	0.9499±1.7
13	Br	13.47±6.2
14	Rb	34.71±6.2
15	Sr	27.65±5.2
16	Y	18.13±5.0
17	Zr	63.7±8.7
18	Nb	6.09±3.29
19	Мо	10.84±4.04
20	Ru	BDL
21	Ag	BDL
22	Pb	28.82±11.2





224 Table-6; G5 sample elements 225 concentrations 231

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S.NO	Element	<i>G5</i>
1	Cl	546.9±23.5
2	K	6699±40.2
3	Ca	4120±23.5
4	Ti	1590±13.8
5	V	37.78±6.0
6	Cr	17.71±3.1
7	Mn	47.43±5.3
8	Fe	7325±26.4
9	Ni	28.29±5.02
10	Cu	BDL
11	Zn	11.96. ±4.6
12	Se	BDL
13	Br	10.32. ±4.031
14	Rb	56.14 ±7.9
15	Sr	38.02±6.5
16	Y	BDL
17	Zr	11.44±7.0
18	Nb	BDL
19	Мо	BDL
20	Ru	BDL
21	Ag	BDL
22	Pb	41.58±14.48

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and 229 Table-7; G6 sample elements and 230 concentrations

S.NO	Element	G 6
1	Cl	383.7±16.7
2	K	5458±27.1
3	Ca	2544±26.2
4	Ti	1044±9.1
5	V	10.79±4.0
6	Cr	9.118±2.1
7	Mn	27.36±3.5
8	Fe	4905±17.7
9	Ni	10.11±3.1644
10	Cu	BDL
11	Zn	24.73±2.9
12	Se	BDL
13	Br	8.61±2.455
14	Rb	34.58±5.3
15	Sr	33.91±4.9
16	Y	BDL
17	Zr	12.16±5.0
18	Nb	BDL
19	Мо	BDL
20	Ru	9.977±3.59
21	Ag	BDL
22	Pb	BDL





233	Table-8;	G7	sample	elements	and	2
234	concentrat	ions				2

S.NO	Element	G 7
1	Cl	462.6±20.6
2	K	5393±33.4
3	Ca	3091±32.1
4	Ti	1510±12.4
5	V	11.55±12.4
6	Cr	14.13±2.6
7	Mn	27.03±4.5
8	Fe	6238±23.1
9	Ni	16.5±4.3692
10	Cu	8.717±3.47
11	Zn	4.29±2.0
12	Se	BDL
13	Br	9.08±3.503
14	Rb	52.46±7.1
15	Sr	35.53±6.1
16	Y	BDL
17	Zr	77.82±9.3
18	Nb	BDL±6. ±6.
19	Мо	BDL
20	Ru	BDL
21	Ag	BDL
22	Pb	24.49±12.5

The PIXE spectrum of the geological samples G1 to G7 collected from the interior of the Charnockite rock recorded by Si (Li) detector. These concentrations are presented with errors in Table-9 assuming Standard Deviation values (n) = 241 7 and BDL (Below Detection Limit).

242 Another attempt is made to analyze 243 the samples using an atomic absorption photo spectrometer and same elements are 244 reported using the method of AAS and the 245 246 same standard also employed for a method of AAS also. The data generated the AAS 247 method has been used to compare the 248 PIXE results for its evaluation purpose. In 249 this paragraph, each element is considered 250 in evaluating PIXE as per that element is 251 252 concentrated.

It is observed that the results obtained by AAS are close which already published data on Charnockites in various journals. The possibility of increasing accuracy of PIXE in analyzing samples of complex matrix like Charnockite has been discussed and suggestions are made.

So, the following tables presents the 260 elements which are close to elements 261 having moderate errors and elements 262 which are highly erroneous not detected. 263 Using this data, the Charnockite hill from 264 where the samples are collected have been 265 attempted to understand the chemical 266 nature followed by genetic implications. 267 The reasons behind the poor performance 268 of PIXE with respect to certain elements 269 270 have been tried to explain.

271 The following tables give overall analysis of Charnockite samples by using 272 PIXE analysis and also AAS analysis. 273 Later the validity of AAS analysis verified 274 through wt% in the major elemental 275 components in the form of oxides in below 276 tables. Finally reviewed the Charnockite 277 278 composition, by using PIXE with 279 comparing results with AAS (tables 9-13).



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S.NO	Element	G1	G2	G3	G4	G5	G6	G7
1	Cl	394.1±16.5	399.6±17.1	379±16.5	403.5±19.5	546.9±23.5	383.7±16.7	462.6±20.6
2	К	4080±28.2	4187±25.1	4148±26.1	4246±29.3	6699±40.2	5458±27.1	5393±33.4
3	Ca	2229±25.9	2281±22.8	2637±25.6	2754±28.1	4120±23.5	2544±26.2	3091±32.1
4	Ti	1394±11.6	1271±9.3	1109±9.3	13.67±11.3	1590±13.8	1044±9.1	1510±12.4
5	V	17.92±4.8	23.69±4.1	7.85±4.0	BDL	37.78±6.0	10.79±4.0	11.55±12.4
6	Cr	16.63±2.3	38.53±2.1	15.16±2.1	16.93±2.5	17.71±3.1	9.118±2.1	14.13±2.6
7	Mn	18.62 ±3.9	34.71±3.7	34.31±3.7	33.68±4.1	47.43±5.3	27.36±3.5	27.03±4.5
8	Fe	5200±20.3	6575±21.0	5649±19.8	5838±22.2	7325±26.4	4905±17.7	6238±23.1
9	Ni	10.96±3.7	11.43±3.7	10.06±3.39	8.94±3.92	28.29±5.02	10.11±3.1644	16.5±4.3692
10	Cu	BDL	BDL	6.1±2.7	BDL	BDL	BDL	8.717±3.47
11	Zn	9.147±3.3	18.21±3.5	14.23±3.0	14.41±3.5	11.96. ±4.6	24.73±2.9	4.29±2.0
12	Se	6.3±65±2.5	BDL	BDL	0.9499±1.7	BDL	BDL	BDL
13	Br	4±2.2	12.17±2.93	11.82±2.85	13.47±6.2	10.32±4.031	8.61±2.455	9.08±3.503
14	Rb	48.87±6.0	42.08±6.1	62.73±6.0	34.71±6.2	56.14 ±7.9	34.58±5.3	52.46±7.1
15	Sr	38.5±5.4	28.6±4.6	44.61±4.9	27.65±5.2	38.02±6.5	33.91±4.9	35.53±6.1
16	Y	BDL	12.64±4.5	BDL	18.13±5.0	BDL	BDL	BDL
17	Zr	95.91±9.8	20.86±6.0	23.6±6.1	63.7±8.7	11.44±7.0	12.16±5.0	77.82±9.3
18	Nb	7.035±3.1	9.812±3.9	BDL	6.09±3.29	BDL	BDL	BDL.
19	Мо	BDL	24.34±6.3	BDL	10.84±4.04	BDL	BDL	BDL
20	Ru	BDL	BDL	BDL	BDL	BDL	9.977±3.59	BDL
21	Ag	BDL	12.36±9.0	BDL	BDL	BDL	BDL	BDL
22	Pb	32.93±15.6	38.35±17.3	17.68±7.7	28.82±11.2	41.58±14.48	BDL	24.49±12.5

Table- 9; Analytical results of all geological samples (PIXE)

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Table-10; Analytical results of all geological samples (AAS).

Element	G11	G21	G31	G41	G51	G61	G71
Na	23483	15561	22300	23718	26679	25505	25306
Mg	20568	16467	20026	20209	20501	24063	17546
Al	89081	90776	87760	96543	88132	89302	90105
Si	260631	274683	265398	269366	265905	262318	261506
Р	1367	1402	916	1103	1231	1450	1582
Cl	-	-	-	-	-	-	-
K	24813	29466	27052	25739	9268	11374	13908
Ca	33709	28918	30776	29412	29418	36403	39305
Ti	7001	7403	7606	7842	6582	7409	7205
V	127	125	136	129	143	137	126
Cr	38	34	39	33	38	31	39
Mn	2023	2706	1855	1784	1548	2202	3011
Fe	87176	69983	88511	71342	90979	86904	87202
Со	8	10	7	9	7	11	7
Ni	38	34	42	45	39	37	42
Cu	8.8	12.8	11.9	9.2	6.6	8.6	11.1
Zn	11.3	12.3	9.3	15.4	10.6	10.9	9.3
Se	6.3	7	4	6	7.4	3.9	5
Br	-	-	-	-	-	-	-
Rb	60.8	70.1	74.6	89	82.9	77.5	71
Sr	144	132	143	126	119	128	148
Y	56	39.5	47.3	49.1	45.8	63.2	46.2
Zr	194.1	189.6	198.9	190.6	189	12.1	12
Nb	15.9	14.5	13.1	12.1	10.9	12.9	12.6
Мо	5.8	6	6	5.3	8	8	6
Ru	4.9	5.9	4.3	4.2	4	6	4.4
Ag	10	4.2	4.1	4.2	7	5	4
Pb	29.3	27.9	31.3	32.4	28	28	32.9
Ba	852	843	839	858	823	857	819

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Table-11; Total Analytical results of all samples (AAS).

Element (Wt.%)	G11	G21	G31	G41	G51	G61	G71
Si	26.063	27.68	26.539	26.936	26.590	26.23	26.15
Al	8.908	9.077	8.776	9.654	8.813	8.93	9.01
Ti	0.7	0.940	0.760	0.784	0.658	0.74	0.72
Fe (total)	8.717	6.99	8.851	7.134	9.097	7.88	8.72
Mg	2.056	1.646	2.002	2.020	2.050	2.406	1.754
Mn	0.202	0.270	0.185	0.178	0.154	0.22	0.301
K	2.481	2.946	2.7058	2.573	0.9268	1.137	1.39
Ca	3.37	2.891	3.027	2.941	2.949	3.648	3.93
Na	2.346	1.556	2.230	2.371	2.667	2.55	2.53
Р	0.136	0.140	0.092	0.110	0.123	0.145	0.158

Table-12; Major Elements of all samples (AAS) Wt%.

Element (wt.%)	G11	G21	G31	G41	G51	G61	G71
Sio ₂	55.81	58.82	56.83	57.68	56.94	56.17	56.01
Al ₂ 0 ₃	16.84	17.16	16.59	18.25	16.66	16.89	17.05
Tio ₂	1.17	1.57	1.27	1.31	1.10	1.24	1.21
Fe ₂ o ₃	1.65	1.39	1.72	1.094	1.289	0.81	0.82
Feo	9.74	7.77	9.85	7.78	10.05	10.15	10.18
Mgo	3.41	2.73	3.321	3.35	3.42	3.51	2.91
Mno	0.262	0.35	0.241	0.23	0.20	0.29	0.39
K20	2.99	3.55	3.26	3.10	1.16	1.37	1.67
Cao	4.72	4.05	4.31	4.12	5.42	5.11	5.31
Na ₂ o	3.17	2.10	3.01	3.20	3.60	3.45	3.42
P205	0.31	0.32	0.21	0.25	0.28	0.33	0.36
Total	100.078	99.81	100.423	100.84	100.58	100.57	100.27





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Table-13; Analytical results of all geological samples (PIXE and AAS).

S. No Element		PIXE(Average values of seven	AAS (Average values of		
		samples, ppm)	seven samples, ppm)		
1	Na	-	23221.70		
2	Mg	-	19911.42		
3	Al	-	90242.71		
4	Si	-	265686.71		
5	Р	-	1293		
6	Cl	424.2±18.62	-		
7	K	4887.28±29.91	20231.42		
8	Са	2808±26.31	32563		
9	Ti	1133.09±10.97	7292.57		
10	V	18.26±5.88	131.85		
11	Cr	18.31±2.4	36		
12	Mn	31.934±4.1	2161.28		
13	Fe	5961.42±21.5	83156.71		
14	Со	-	8.42		
15	Ni	13.755±3.89	39.5		
16	Cu	7.40±3.08	9.85		
17	Zn	13.85±3.25	11.3		
18	Se	3.65±2.1	5.65		
19	Br	9.92±3.45	-		
20	Rb	47.36±6.37	75.12		
21	Sr	35.26±5.37	134.28		
22	Y	15.385±4.75	49.585		
23	Zr	43.64±7.41	140.9		
24	Nb	7.6±3.43	13.14		
25	Мо	17.59±5.17	6.442		
26	Ru	9.97±3.59	4.20		
27	Ag	12.36±9.0	5.5		
28	Pb	30.64±13.13	29.97		
29	Ba	-	841.57		

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299 Another attempt is made to analyze the samples using Atomic Absorption photo spectrometer for PIXE fig; 1-7 evaluation or standardization Christopher et. al., (2016) in 300 301 high grade matrix composition and the same elements are reported and same standard also employed for a method of AAS. The data generated the AAS method table-10 to 13 has been 302 used to compare the PIXE results Oti Wilberforce JO (2016) for its standardization purpose. 303 304 In this paragraph each element is considered in evaluating PIXE as per that element is 305 concentrated. It is observed that the results obtained by AAS are close which already published data Rao and Babu (1978) Sriramadas and Rao (1979) Charnockites in various 306 journals Saradhi (2000) Rajib Kar (2001) With respect to certain elements, the reasons behind 307 the improper performance of PIXE in case of matrix composition of geological materials 308 have been tried to explain Gerlad, et. al., (1993). 309





310 It is established that the recent advances in PIXE can successfully used in analyzing samples with high accuracy, precision, low detection limits and high resolution from different 311 312 fields like geology of high grade metamorphic rocks. Low energy PIXE, high energy PIXE, 313 micro PIXE and external beam PIXE are recent developments which are used to determine the various elements present in samples in the form of major, minor and trace amounts from 314 low to high atomic (Z) elements. During recent advances in PIXE, it is indicated that the 315 316 spatial resolution of peaks of various elements in samples of materials can be obtained in the order of micro meter by developed micro PIXE and hence elimination of overlapping of 317 peaks in matrix effects are possible. 318

319 The detailed study table-1-13 of Charnockite samples from Visakhapatnam have been established that there is certain accuracies pertaining to the concentration of certain elements. 320 321 Potassium is a major element in the Charnockite composition. The concentration of K in the Charnockite composition by PIXE ranges from 4000 to 6000 ppm range in various locations. 322 But actually according to contents of Charnockite composition its value should be 20,000 323 324 ppm range. This is due to overlapped peaks of Ca K X-ray with K K X-ray in spectrum obtained in this investigation. From this analysis PIXE is unable to detect major elements in 325 326 Charnockites of Visakhapatnam due to detector limits. Calcium is also a major composition of Charnockite composition like potassium and in the analysis of Charnockites by using 327 PIXE, its value is 2500-3000 ppm range in all G1 series to G7 series samples. But in the 328 analysis of AAS its value is 30,000 ppm range. Therefore, PIXE once again fails to detect 329 exact value of ppm of major elements like K and Ca in Charnockite composition. The K and 330 Ca escape peaks in Si (Li) detector interfere with X-ray lines of Al, Pand S; K and Ca 331 summing peaks could interfere with X-ray lines of Fe, Ni and Cu. So in case of Charnockites 332 also high K and Ca contents, could be automatically resolved by GUPIX. The K and Ca 333 escape peaks in Si (Li) detector interfere with X-ray lines of Al, Si, P, Na and Mg; K and Ca 334 summing peaks could interfere with X-ray lines of Ti, V, Fe, Ni and Cu in Charnockite 335 336 composition.

337 The concentration of Ti in Charnockite by using PIXE method nearly 1200 -1400 ppm in 338 all types of samples. The error percentage of Ti is 3.6% only by standard reference. But 339 according to previous literature weight ratio in Charnockites it should be 7000 ppm and also by present AAS analysis. From this PIXE analysis the error due to Ti-K α and Fe-K α have 340 341 closely 4.5 keV energy X-rays (4.509 and 4.647 keV) and also Ti-Ba have same X-ray energies (4.469 and 4.509 keV). So PIXE not given proper value in case of major elements 342 343 like Ti due to above overlapping peaks. The value of Fe detection in Charnockite samples by PIXE is around 6550 ppm but by the investigation through AAS its value is 86,000 ppm, 344 345 which is equal to wt% of Charnockite composition study. PIXE could not perform well in the determination of Fe. Because the overlapped of Co-K α and Fe-K β causes the inability of proper 346 detection and in addition to that Ti-K α and Fe-K α are same energy or nearly K X-ray energies, 347 (4.509 keV and 4.647 keV.) Some times it is difficult to resolve two peaks from neighboring 348 349 elements. Some corrections are needed to calculate the exact concentration value of Fe in 350 Charnockites by PIXE.





PIXE unable to detect the low Z elements present like Li, Be, F, Na, Mg Al, Si and P in 351 Charnockites due to detector limits. X-rays below or near the sodium cannot be seen because 352 353 they are absorbed in either the detector window atmosphere or though any filter used. A possible disadvantage to running in this configuration is that low energy X-rays from lighter 354 elements attenuated in air. By increasing efficiency of detector or placing more suitable 355 detectors of by changing the incident proton beam energy or other technique like AAS used 356 357 in this investigation, these low atomic number (Z) elements are determined. Another reason also is K and Ca escape peaks of in this investigation in Si (Li) detector interfere with X-ray 358 lines of Be, F, Na, Mg, Al, Si, and P Ana, et. al., (2011). The concentration of element V in 359 360 this PIXE analysis, 28-30 ppm and by AAS the value is 125ppm. From the above values 361 PIXE nearly gives results in case of minor elements and middle Z elements due to nonoverlapping of peaks and spectrum obtained by PIXE. The remaining 100 ppm due to Ti 362 363 overlapped peaks in the spectrums of Charnockite samples. So PIXE is more suitable in the analysis of minor elements, middle atomic number (Z) elements. The error percentage of V is 364 365 around 15% through standard reference material.

PIXE results showed very good approximation in case of minor element .In case of Co 366 367 elemental analysis of Charnockite rocks by present PIXE investigation; the ppm value is not detected. But Co trace presented in Charnockites according to previous literature and 368 composition of Charnockite by AAS. Non determination by PIXE of Co in Charnockites is 369 370 due to mainly two reasons; 1) Co- K α and Fe- K β 2) Ni K α and Co K β from the interferences of above two peaks trace of cobalt not detected, but in case of AAS analysis Co also 371 presented in Charnockites and its value only is 8 to 10 ppm. In this case also Fe is the major 372 component so that the X-ray emitted from this element will dominate the energy spectrum, In 373 374 the PIXE analysis of Charnockites, the elemental concentration of Cu is very low and only traces of one or two samples are obtained. But by using AAS analysis traces of Cu up to 12 375 ppm are present. The above reason is due to the interference of Cu peak with Zn peak in case 376 377 of Charnockites samples from Figure 3.1 to 3.7. It is Cu Ka and Zn KB interference matrix, i. e, K α (Z+1) X-ray and the K β (Z) X-ray and by correction small interference value, PIXE 378 379 once again proved in the detection case of trace elemental analysis.

380 By present PIXE analysis, the concentration value of Cr in Charnockite samples is 10-20 ppm and by AAS analysis, the value is also the same 40 ppm. Like V, in this case also 381 382 obtained the same result by PIXE analysis. Here no overlapping of peaks with V element in the spectrums as shown in Figure 1 to 7. PIXE again given nearly good results in case of 383 minor elements as stated above in case minor elements, middle Z elements with small matrix 384 corrections. The concentration value of Mn obtained by PIXE analysis investigation is 20-40 385 ppm and AAS analysis its value is 2000 ppm. In this case variation is due to the matrix of 386 non-resolution of peaks between Mn K β and Fe K α overlapped. The error in this by using 387 388 standard reference material is 1%. So correction is required in case of Mn concentration which is determined by PIXE analysis and also suitable to measure the concentration of Mn 389 390 major element with correction of matrix effects. Because in Charnockites Fe is the major component. So the X-ray emitted from this element will dominate the energy spectrum as can 391 392 be seen from Figure; 1 to.7 and influence the Mn peak and concentration.





The concentration value of Ni by PIXE analysis is 10-20 ppm and ASS analysis is 40 393 ppm. In this element PIXE analysis given excellent result when compared with AAS and 394 395 remaining 20 ppm is due to the interference and non-resolution of peaks obtained by PIXE with cobalt traces due to Ni K α with Co K β . The error percentage in this case is 2% and 396 except 20 ppm correction compared to AAS and previous literature, PIXE given excellent 397 result in nickel minor elemental concentration of Charnockites. The concentration of Zn 398 element in samples of Charnockites by PIXE analysis, value is 10- 20 ppm range but the 399 results obtained by AAS its value is 10-15 in eastern ghats, Charnockites, Visakhapatnam. 400 The variation between the above two analysis, the error percentage of Zn though standard 401 402 reference is 16% and 5-10 ppm the variation between the above two analyses, which is very 403 low and good results obtained by PIXE analysis. So the variation of above value with AAS is due the above Cu and Zn peaks overlapped in spectrums of Charnockites obtained by PIXE 404 405 analysis. In this case of Sr, the PIXE analysis 30-40 ppm range and AAS analysis 140 ppm and difference 80 ppm, Sr K α and Rb K β and also with Y K α X-rays overlapped corrections 406 407 due to error value 3.5%. The PIXE had given the same results like above minor elements. The concentration values of Rb obtained by PIXE and AAS are 40-50 ppm and 60 ppm. The 408 409 difference is nearly 20 ppm range and this is due to the overlapped peaks of Y K α and Rb K β , Sr K α and R K β in the analysis of spectrum of the peaks of Charnockites. So by correct the 410 matrix20-30 ppm value of Rb and compared to AAS, PIXE has given good results in case of 411 Rb. 412

Using PIXE analysis, the concentration value of Y is 10-15 ppm which is low. From 413 Charnockite composition and present AAS analysis, its value is 60 ppm range and the 414 difference arises due to Y K α and Rb K β overlapped of peaks and matrix effects. From the 415 above two elements if the concentration value increases, PIXE performance value decreases. 416 By PIXE analysis the concentration value is 90 ppm and by AAS analysis its value is 190 417 ppm. From these analyses PIXE analysis is very poor in the detection of Zr and resolution of 418 419 peaks with Nb. The poor results obtained in PIXE analysis of element Zr in the Charnockites as concentration value of element in Charnockite composition increases, poor results also 420 421 increase in PIXE analysis. It is same as above two cases. The error value increases with as 422 concentration value increases.

The concentration value of Nb in Charnockites is 5-11 ppm in PIXE and in case of AAS 423 424 its value is 15 ppm range, the concentration variation is only 10 ppm and it is due to small matrix effect of Zr and Mo. Of course, PIXE analysis is good in case of trace elements like 425 Nb except small corrections due to resolutions of peaks and matrix effects. The element Pb is 426 an important element in rock formation, which is determined by PIXE and its value 20-30 427 428 ppm range and in the investigation of Pb, PIXE given good results. It gives valuable information in rock crystallization process. In PIXE analysis, the concentration value 429 430 identified is only 1-2 series samples of Charnockites. So in PIXE analysis traces of Mo not 431 exactly found due to corrections of interferences with Nb but its value by AAS is also given 432 very low traces due to matrix effect of Nb.





433 The traces of Ru found by using PIXE like Ag in Charnockites. AAS analysis is also given only traces of Ru in one or two sample series of Charnockites. It is a precious metal 434 435 previously not detected in Charnockite, in this PIXE also not trace out exactly because in ppb levels and most of above series samples are at BDL. So PIXE is suitable to measure the 436 concentration of precious metal like Ag. The traces of Ag investigated also in the AAS 437 analysis. It is an important element in Charnockites in Visakhapatnam and these are halogen 438 rich minerals. PIXE is a very suitable technique in the determination of gaseous phase 439 440 elements like Cl. Its value is 400 ppm which is the similar result obtained by previous analysis. But AAS is not able to detect the Cl element directly.Br is also a trace element in 441 442 halogen rich minerals of Charnockites. PIXE is very suitable in the detection of Br and Cl but not F present in the composition due X- ray energy limitation. The gaseous elements give 443 information about rock formation. The traces of Br identified by the PIXE are in the range 5-444 13 ppmand Br is not detected by AAS. PIXE is very much suitable technique in case of 445 middle Z elements like Zn, Rb, Cr, gaseous elements Cl and Br, in the detection of precious 446 447 metals Nb, Mo and Ru and other elements with corrections.

The presented PIXE technique is known for its sensitivity, accuracy, precision simplicity 448 449 and fast of thick target preparation and to perform multi elemental analysis of a large number of complex geological materials like Precambrian, proto crustal rocks compared with the 450 previous study EPMA. By the identification of elements from upper mantle, crust and the 451 452 trace elemental data show that rock samples analyzed have a composition different from that of the host Charnockite. These include the large ion lithophile elements (Rb, Sr) high field 453 strength elements (Ti, Zr, Nb) precious elements Ag, Cu and various elements of importance 454 in geo thermo barometry. However for REE elements, the LOD are markedly poorer. This is 455 456 particularly the case for the REE s Hajivaliei, et. al., (2000):

The elements K, Ca, Rb and Sr present in high concentration, low value of Ni in the 457 samples supports calcium alkaline phase. The element Fe has the highest concentration, Cr, 458 Zn and Zr are detected in the samples strongly indicates the ultramafic percentage from upper 459 mantle. In this aspect these rocks are entirely different from the host Charnockite and these 460 461 were evolved from upper mantle to crust during Precambrian period. The light and medium 462 heavy elements therefore determined by their K X-ray as the heavy ones by L X-rays which are shown in figures. PIXE has certain drawbacks in detection of light elements Be, F, Na, 463 464 Mg, Al, Si, and P and the REE. For light elements, the problem is mainly due to absorption of the low energy X-ray Durocher, et, al., (1988) by detector Si (Li) windows and the tails of the 465 heavier major elements peaks. 466

PIXE, especially with micro beam, has proven to be a versatile and powerful analytical tool in many areas of geology. PIXE within a short span of time has demonstrated its versatility and usefulness by the diversity of applications to which it has been applied. The detection limits of the PIXE measurements were calculated assuming that the minimum detectable peak is three times the square root of the background at FWHM. The detection limits in the PIXE measurements 0–1ppm by weight with the exception (from all the tables and values presented). We are aware of no attempts having been made to apply PIXE analysis





to the petrogenesis of intermediate to silicic igneous rocks. Our results show that such studiesare feasible.

The ability to analyze diverse phases using a single standard and uniform operating 476 conditions largely obviates the need to perform laborious mineral separations, formerly 477 necessary for studies of the trace-element inventory of such rocks. Among the most exciting 478 potential applications of PIXE analysis to silicate minerals and element-partitioning 479 480 measurements relevant to mineral melt, mineral-mineral, or melt-melt systems useful in understanding melting and crystallization processes, trace element zoning studies in igneous 481 482 or metamorphic volcanic minerals to assess the crystallization behavior of magmas or to 483 assess tectonic and metamorphic histories and diffusion-profile measurements in minerals, 484 melts.

In the coming years PIXE should find itself being applied more and more to a variety of 485 samples, when a rapid non-destructive and multi-elemental method is looked for and it should 486 487 take its rightful place as an equal or better technique among the numerous other standard analytical techniques available. We also demonstrated that nuclear microscopy, due to its 488 high spatial resolution and the low detection limits proved to be a powerful tool for the 489 490 characterization of minerals with complex chemistry and it serves as an ideal complementary 491 technique of optical mineralogy, SEM and EPMA. During to its longer probe depth (ten of micro meter) the PIXE can be performed for a large range of elements (K \leq Z \leq Pb) in the 492 493 periodic table. So PIXE useful fast, precise, accurate and sensitive (limit in ppm). Both matrix and trace elements PIXE gives higher signal to background ratio as compared to 494 495 EPMA and spectrum 100 times better sensitive and has higher resolution like previously 496 stated.

Compared to electron based X-ray analytical techniques such as energy dispersive 497 spectroscopy(EDS) and EPMA, PIXE offers better peak to noise ratios and consequently 498 499 much higher trace element sensitivities as seen in spectrum Figure 1 to 7. PIXE is capable of multi-elemental analysis and a large number of elements (Twenty two) may be seen 500 501 simultaneously. PIXE, being a non-destructive technique and because the original shape and 502 size of the sample is not destroyed, makes it a unique facility for a number of applications. PIXE and XRF are both methods based on X-ray emission and have several features in 503 common. From sensitivity point of view, PIXE has certain superiority, moreover the 504 bremsstrahlung produced in PIXE is a secondary effect where as in case of Electron 505 Microprobes and XRF it is primary contributor and the principal source of proton back 506 507 ground against which the character X-rays of elemental constituents must be distinguished and hence is also the principal determinant of detection limits. The low bremsstrahlung in 508 509 PIXE enables parts per million sensitivities, superior to its sister techniques in geological materials are obtained (From previous literature and previous EPMA and XRF). 510

The results obtained indicate that it is competitive with other more classical analytical methods, and that it may be, in addition, a very useful complementary technique when combined with other ion beam methods like PIGE, EPMA, XRF and NAA is, in general, a





very sensitive method but has limited use for light elements. Also, Particle-Induced X-ray Emission (PIXE) fails in the situation where the species of interest has a low atomic number because the low K X-ray fluorescence yields are strongly attenuated by the absorption edge of higher atomic number elements present in the sample. Prompt γ -ray analysis (PIGE) offers an alternative in measuring light elements which are not detected by PIXE and has the advantage that γ -rays from the different light elements can be easily distinguished by their energies. The sensitivity of PIGE analysis can be improved by coincidences measurements.

From this it results that by coupling PIGE, PIXE and NAA methods, a very good overall 521 picture of the elemental composition of a complex target such as steel may be obtained. PIXE 522 523 and NAA are complements of PIGE when the determination of medium and heavy elements with high sensitivity is necessary in geological materials. Neutron activation is a very 524 525 efficient tool of high sensitivity, but it is expensive and seldom used; also this technique is not convenient for detection of some elements of great interest in geochemistry such as Al, Si 526 or Pb. But detection of Pb possible in this PIXE, off course light elements like Al, Si not 527 detected but light elements are possible by using PIGE. 528

The method is a very sensitive one having a minimum detectable concentration of about 529 530 0.1-1 ppm under optimum conditions. In the coming years PIXE should find itself being applied more and more to a variety of samples, when a rapid non-destructive and multi-531 elemental method is looked for and it should take its rightful place as an equal or better 532 533 technique among the numerous other standard analytical techniques available. PIXE analyses of silicate samples are of excellent quality for a broad range of elements at abundance levels 534 535 of one to hundreds of parts per million, depending on counting times. PIXE with Si (Li) detector not suitable to detect REE because in the determination of REE in geological 536 537 samples is a very important subject but hard to tackle. By PIXE the L X-rays energies from 4-9 keV strongly overlap with K X-rays energies of light elements (20 to 30 Z). 538

539 The quantification of REE by PIXE becomes very difficult and inaccurate as results of the needed complex spectrum deconvolution. In fact in the context of REE L X-ray using 540 standard PIXE set by compared results obtained with PIXE, XRF and NAA for geological 541 samples and concluded that with the PIXE technique the limits are 30 ppm for REE, higher 542 than with other techniques as NAA. The use K X-ray of REE elements could be a solution 543 but at that energies Si (Li) detection can no longer is used. To overcome this problem the use 544 of large Ge detection to detect the L X-ray of REE was attempted but due to large 545 dimensions, a large Compton back ground is present which degrades the detection limits in 546 547 the high X-ray energy region. Small Ge detection represent in improvement relative to this problem. But their overall size is still significative to this problem. But their overall crystals 548 549 reduced solid angle Cd Te detects have average atomic numbers of 50 allow the construction of small detection. 550

PIXE roughly analyses the element whose atomic numbers, the light and medium-heavy
identified by their K X-ray and the heavy elements by L X-ray due to the effective detection
of the K X-ray which can be obtained in the range 20<Z<50, L X-ray for Z>50 and 20<Z<50





for M X-ray. So due to above reason Na, Al, Si, and Mg not detected due to low Z elements
(Z<17) in this investigation.

PIXE fails in the situation where the species of interest has a low atomic number because 556 the low K X-ray fluorescence yields are strongly attenuated by the absorption edge of higher 557 atomic number elements in the present investigation. From the above results, PIXE at IOP, 558 Bhubaneswar, India, Charnockites elemental analysis lower atomic number(Z) in all 559 spectrums is Cl (Z=17) and higher atomic number (Z) in all spectrums is Ag (Z=47) for K X-560 ray. For L X--rays only Pb is present in charnockites (Z greater than 50). The comparison with 561 roughly PIXE (20<Z<50 for K X-ray and Z>50 for L X-ray), good results obtained by PIXE 562 in the elemental analysis of Chatnockites of airport hill Visakhapatnam. 563

The element Sc is a trace which is detected previously by nuclear techniques other than PIXE. But in this investigation above element is not detected due to the X-ray K α =4.093 keV is equal to the K β =4.013 keV of Ca and hence resolution of Si (Li) detector at 160eV at 5.9keV. Simillarly K β =4.464 keV of Sc is equal to K α =4.512 keV of Ti. The element Y is also trace is not detected properly by present PIXE because Y K α =14.958 is equal to Rb K β =14.961 keV and Y K β =16.739 keV is equal to Nb K α =16.615 keV.

570 Again from this analysis, PIXE once again proved with good accuracy with $\pm 11\%$ in the detection of elements present in samples, better resolution in case of all elemental peaks with 571 detection limits <1 ppm with precious trace elemental detection through sensitivity. Non 572 detection of Th and U by PIXE in this investigation depend detector window. It can be 573 performed for a large range of elements (K<Z<Pb). The lower limit started from Z=17(Cl) is 574 575 due to experimental detector limits because PIXE analysed the elements present in samples 576 from Z=17(Cl) to Z=Pb (82) (from previous literature and present investigation also). So eventhough some elements are present in eastern ghat Charnockite from previous analysis 577 like XRF and EPMA, here not detected because of detector efficiency. Ba was detected 578 579 previously in the major element category of Charnockites like XRF analysis but it is not possible due to following explanation. In case of PIXE, the light and medium-heavy elements 580 are identified by their K X-rays and the heavy elements by L X-rays. Due to the effective 581 582 detection of the K X-ray which can be obtained in the range 20<Z<50 and of the L X-ray for 583 Z>50. Since the value of atomic number (Z) of Ba is 56, this element is not suitable to detect by PIXE. Similarly, the middle Z elements Sc, Ce, Sn, W, Ge, Ga and also Au not detected 584 due to overlapped. 585

586 3.1. Rare Earth Elements Interpretation

587 Non detection of REE elements is due non suitability of Si (Li) detector to the REE 588 elements in PIXE. These samples belong to a very important geological phase and further 589 work on petrography and REE of the rock is indeed to firmly establish its exact parentage. 590 PIXE has weaknesses in detection of media Z elements (Ti, V, Mn, Cr, Fe, Ni, Co) and the 591 REE. For light elements, the problem is mainly due to absorption of the low energy X-ray by 592 detector Si (Li) windows and the tails of the heavier major elements peaks. One approach,





such as that will be tried to use ultra thin window for X-ray detectors. This enables to extend
the lower limit of detectable atomic number but measures must be taken to protect the
detector from scattered proton beams, for example by using magnetic beam deflector.

Poor REE detection is due to the fact that the L-X-ray are either absorbed heavily or 596 interfered with by the K α line of Fe which is present in most geological rock samples with 597 598 low energy proton. The K and L X-ray production cross section and intensity ratios of rareearth elements for proton impact in the energy range 20-25 MeV are useful for detection of 599 trace elements in rare earth region due to their high K X-ray ionization cross-section 600 Hajivaliei, et. al., (2000). The use of their K X-ray is not practical because of the low yield 601 602 and the low efficiency of the Si (Li) detector for X-ray>30 keV. Improvements in the future would address these problems and include the use of Ge detector or WDS detector in 603 604 principle. PIXE, being a non-destructive technique and because the original shape and size of the sample is not destroyed, makes it a unique facility for a number of applications for the 605 determination of REE of samples needed. 606

607 3.2. Other Traces Elemental Interpretation

608 The trace of element bromine is not all detected previously in Charnockite hill of 609 Visakhapatnam by previous methods like EPMA and XRF. This investigation by PIXE clearly proved that this technique could detect not only regular elemental phase Cl in halogen 610 rich minerals of Charnockites, and also the trace of Br. This aspect is highly interesting and 611 potential geological applicability in similar investigations. From these fluids containing rich 612 in Cl, F and also trace of Br are recognized to have contributed significantly to the evolution 613 of proto crust. In this PIXE technique element, F is not detected due to PIXE has weaknesses 614 in detection of light elements (F, Na, Mg,, Al, Si, and P). 615

616 Here the silver identified in some few samples, it is an interesting investigation. Previous methods not identified this type of precious metal in analysis and no method from 617 Charnockite analysis identified the precious metal Ag. So PIXE is wonderful technique used 618 to identify the traces of Ag in Eastern Ghat Charnockites particularly in high metamorphic 619 rocks. PIXE is a sensitive technique in the analysis elements even though if they are present 1 620 621 micro gram/gram through scan the sample even small quantities are present in few samples. Nb is also present in few samples in the order of below 10 ppm. From this analysis PIXE has 622 623 higher sensitivity with accuracy without destroy the sample and is very important in case of precious metals like Nb. Previous analytical techniques like XRF and EPMA except PXE, 624 trace of Cu not detected in Charnockites of Visakhapatnam. The PIXE once again proved in 625 case of traces present even though if they are present in one or two samples in ppm levels. 626

The importance of PIXE technique is used to find out the new trace elements if they are present even in small quantities at any corner of sample even in micro gram. Previously in Eastern Ghats analysis in any method Se and Mo not identified but in this investigation they are in clearly appreciable quantities in few samples. This kind of experimental research work may be compared with the previous work published in elsewhere, accuracy evaluation





632 absolute calibration in thick target PIXE. Data have been compared with the standard used mainly USGS. Similarly data are compared with elemental concentration obtained for the 633 634 samples studied using another standard technique AAS. In the above paragraphs the PIXE has been evaluated based on the data pertaining to various elements determined. The 635 evaluation has been made and comparing the accuracies of elemental concentration with 636 respect to Charnockite sample. The traces of Th, U also present in charnockite composition, 637 in the PIXE analysis not detected due to X-ray energy limits. Because of wide range of 638 elements from low atomic number Z to high atomic number present in matrix composition of 639 geological materials and characteristic X-rays of any series of elements present are at similar 640 641 to characteristic X-rays of thorium and uranium in composition.

642 4. Conclusions

In support of our observation also the theoretical back ground behind on performance of
PIXE against induced elements has been discussed in detail. An analysis is made to
understand the results behind the poor performance of PIXE with respect to certain elements.
The possible reasons behind this have been brought out.

647 The general observation of PIXE methodology indicate that PIXE has been operated at 648 one 3MeV proton energy with such condition the determination of different elements from low Z to high Z is not possible and perhaps this is the most important reasons behind the poor 649 performance of PIXE with respect to the certain elements. It is suggested that with an 650 651 investigation of PIXE by analysing pure samples of problematic elements. It means them 100% pure elemental powders needed to be analysed with different concentrations at 652 653 different levels using a non interfering matrix so that the optimum conditions for that element can be obtained. Further work is needed to understand the problems pertaining to 654 combinations of elements. Such experiment is needed to design to determine different 655 elements in a sample in combination to an optimum condition of analysis. In this way the 656 conditions of PIXE can be standardized for low Z to high Z elements under different 657 combinations. This kind of experimental research is highly necessary to fine tune the 658 performance of PIXE especially when dealing with materials of complexity like high grade 659 660 metamorphic such as Charnockite.

The present study could establish this aspect for the first time which will help in future
 for effective analysis of complex samples using PIXE. This experiment should contribute the
 conditions of PIXE operation for materials of different complexity and matrix.

The presented PIXE technique is known for its sensitivity, accuracy, precision simplicity of thick target preparation and to perform multi elemental analysis of a large number of complex geological materials, like Precambrian, proto crustal rocks. This investigation clearly proved that this technique could detect not only these elemental phases but also the concentrations of gaseous elements like Br, Cl. And K, Ca, Rb, Sr present in high concentration in the samples supports calcium alkaline phase and also Fe has the highest concentration, Cr, Zn, Zr are detected in the samples strongly indicates the ultramafic

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percentage from upper mantle. This aspect is highly interesting and has partial geologicalapplicability in similar investigations

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